

## 1. Problem statement

**Study of the properties of matrices containing the distance between points  $\mathbf{x}_i$  and linear varieties  $\mathcal{F}_j = \left\{ \mathbf{f} : \mathbf{f} = \mathbf{p}_j + \sum_{\ell=1}^k \mathbf{v}_j^\ell t_\ell \right\}$  of dimension  $k$  and reconstruction of the configuration based on distance measurements.**

Key terms: Euclidean distance, linear varieties

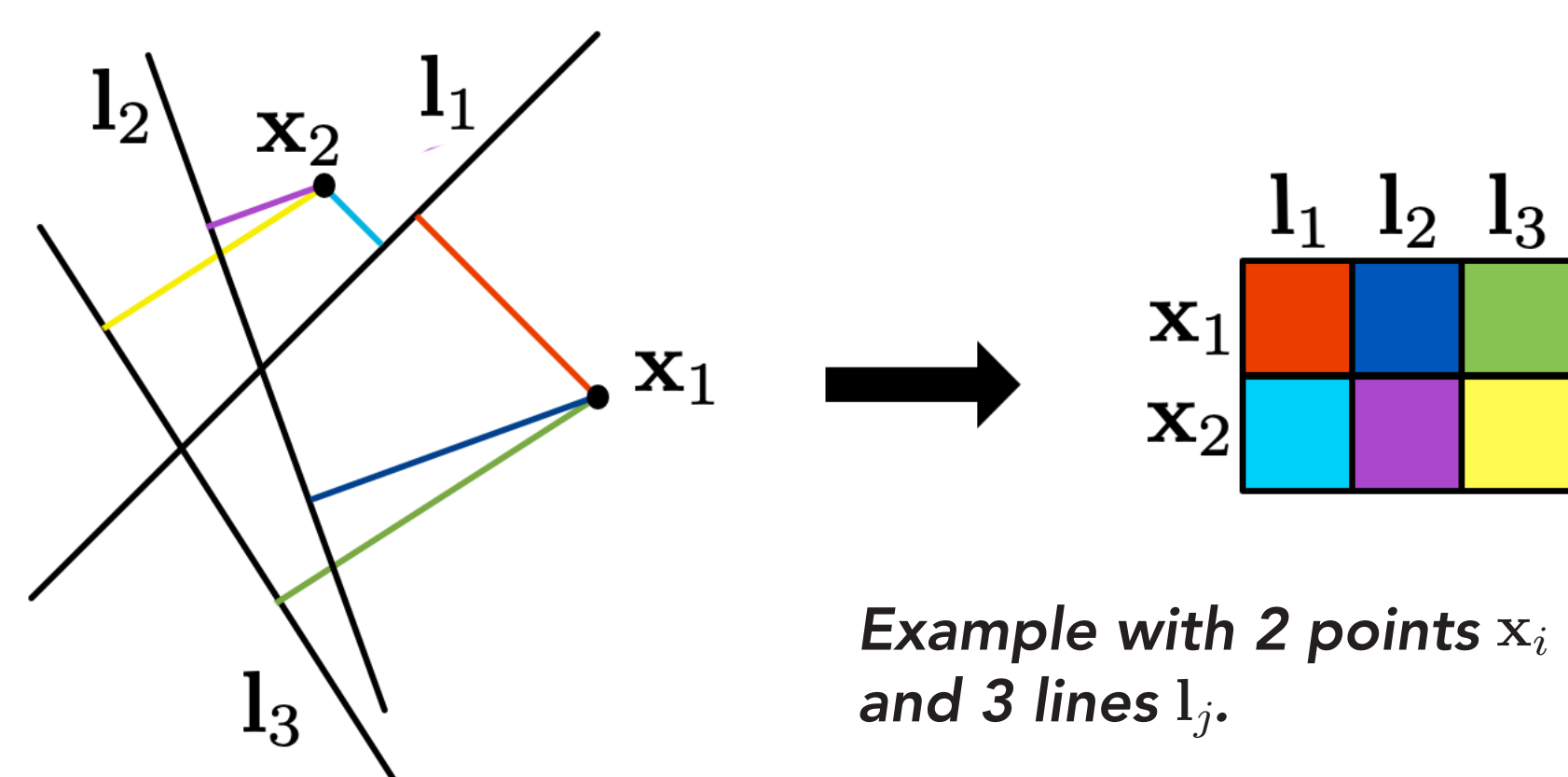
## 2. Distance matrix

For linear varieties  $\mathcal{F}_j$ , we assume  $\mathbf{p}_j^T \mathbf{v}_j^\ell = 0$  and  $\|\mathbf{v}_j^\ell\|^2 = 1$ ,  $1 \leq \ell \leq k$ . The chosen metric to compute the distance between two linear varieties  $\mathcal{F}$  and  $\mathcal{G}$  given by the parametric pairs  $(\mathbf{p}, \Phi)$  and  $(\mathbf{q}, \Psi)$  is:

$$d(\mathcal{F}, \mathcal{G}) = \min_{\mathbf{f} \in \mathcal{F}, \mathbf{g} \in \mathcal{G}} \|\mathbf{f} - \mathbf{g}\|^2 = \|C(\mathbf{p} - \mathbf{q})\|^2,$$

where rows of  $C$  form an orthonormal basis for  $\mathcal{N}(\Phi^T) \cap \mathcal{N}(\Psi^T)$ . This metric makes the distances invariant to rigid motion of the whole configuration.

Symbol	Notation	Corresp. Matrix
$\mathbf{x}_i$	Point $i$	$X \in \mathbb{R}^{d \times n}$
$\mathcal{F}_j$	Linear variety $j$	-
$\mathbf{p}_j$	Intercept of linear variety $j$	$P \in \mathbb{R}^{d \times m}$
$\mathbf{v}_j^\ell$	$\ell$ -th direction vector for linear variety $j$	$V_\ell \in \mathbb{R}^{d \times m}$
$d_{ij}$	Distance between point $i$ and linear variety $j$	$D \in \mathbb{R}^{n \times m}$



Example with 2 points  $\mathbf{x}_i$  and 3 lines  $\mathbf{l}_j$ .

In the special case of distance between points  $\{\mathbf{x}_i\}_{1 \leq i \leq n}$  and linear varieties  $\{\mathcal{F}_j\}_{1 \leq j \leq m}$ , the distance matrix can be written as:

$$D = \text{edm}(X, P) - \sum_{\ell=1}^k (X^T V_\ell)^{\circ 2},$$

where  $\text{edm}(X, P)$  contains the distances between the columns of  $X$  and the columns of  $P$ .

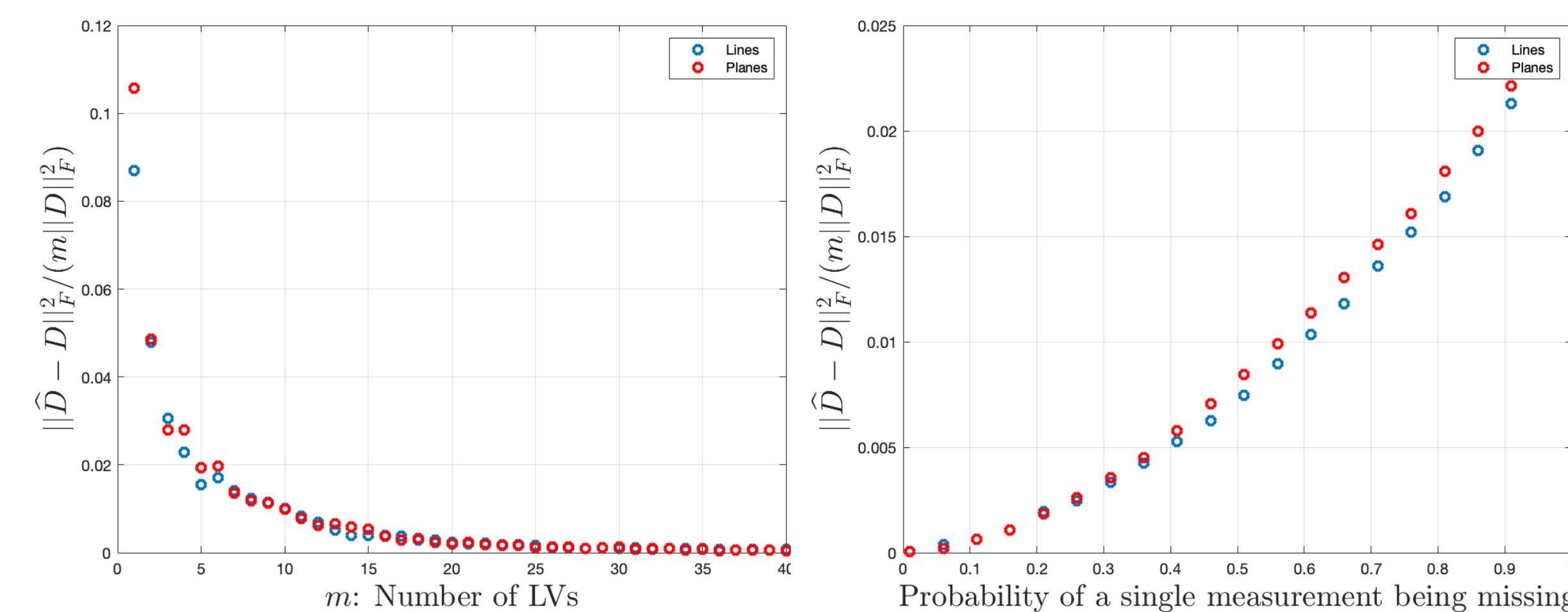
## 3. Completing the distances

The measurements are modeled by  $\tilde{D} = M \circ (D + Z)$ , where  $M$  corresponds to a mask matrix putting to 0 missing measurements and  $Z$  represents the additive measurement noise. How to estimate the true values?

**Theorem 1.**  $\text{rank}(D) \leq d + 1 + \binom{d+1}{2}$ , where  $d$  is the dimension of the ambient space.

**Proposed method:** Applying the singular value decomposition to  $\tilde{D}$ , we construct a low-rank approximation based on the result of

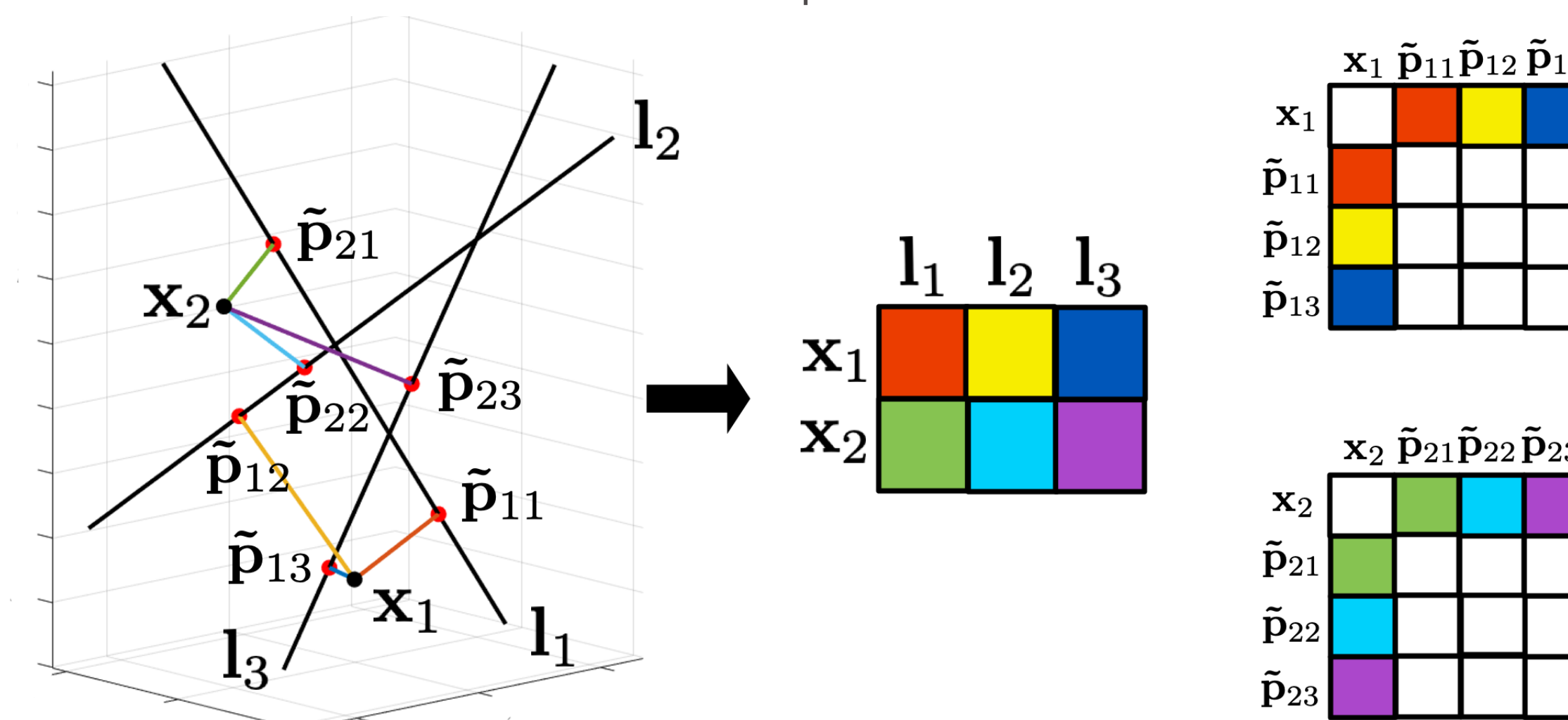
**Theorem 1:**  $\hat{D} = \sum_{i=1}^r \tilde{\sigma}_i \tilde{\mathbf{u}}_i \tilde{\mathbf{w}}_i^T$ . The procedure is iterated by alternating between the low-rank approximation and forcing the known entries, i.e. where the mask is non-zero.



Estimation error for growing number of linear varieties (left) and probability of missing measurements (right).

## 4. Reconstructing the configuration

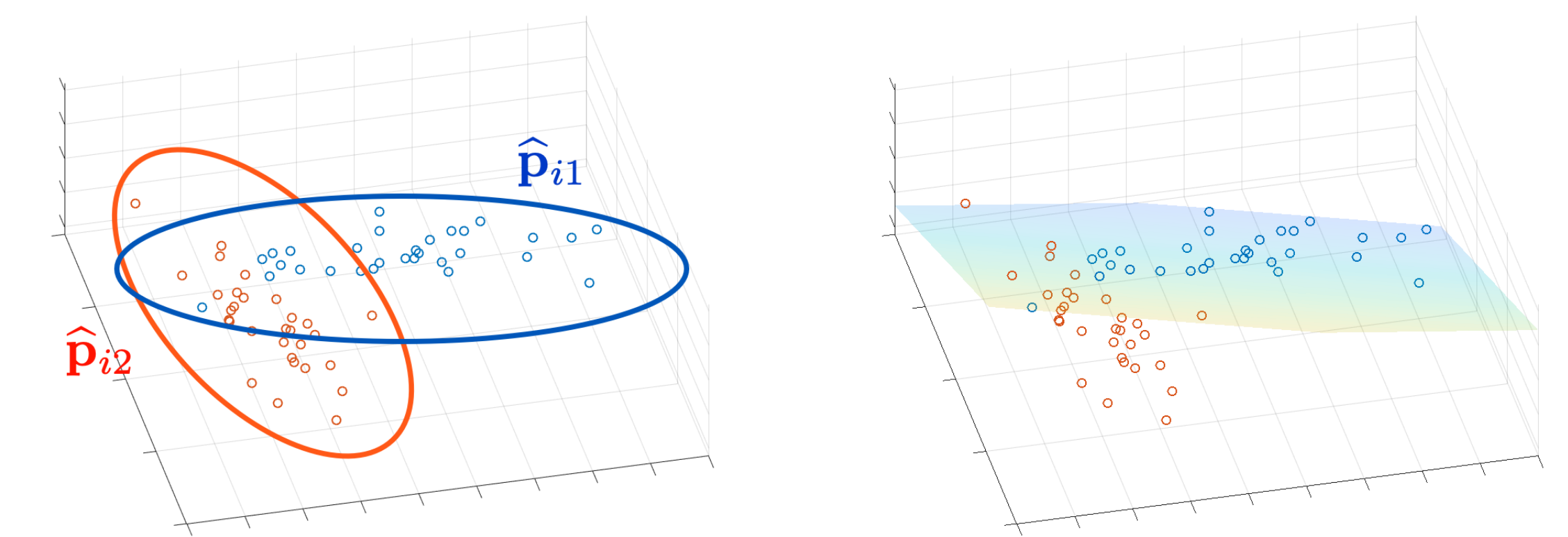
**Proposed method:** The point on linear variety  $j$  where the minimum distance with point  $i$  is obtained is  $\tilde{\mathbf{p}}_{ij} = \mathbf{p}_j + \Phi_j \Phi_j^T \mathbf{x}_i$ , therefore, the distance matrix can be decomposed to  $n$  different EDMs, and the problem is translated to EDM completion.



Decomposition procedure.

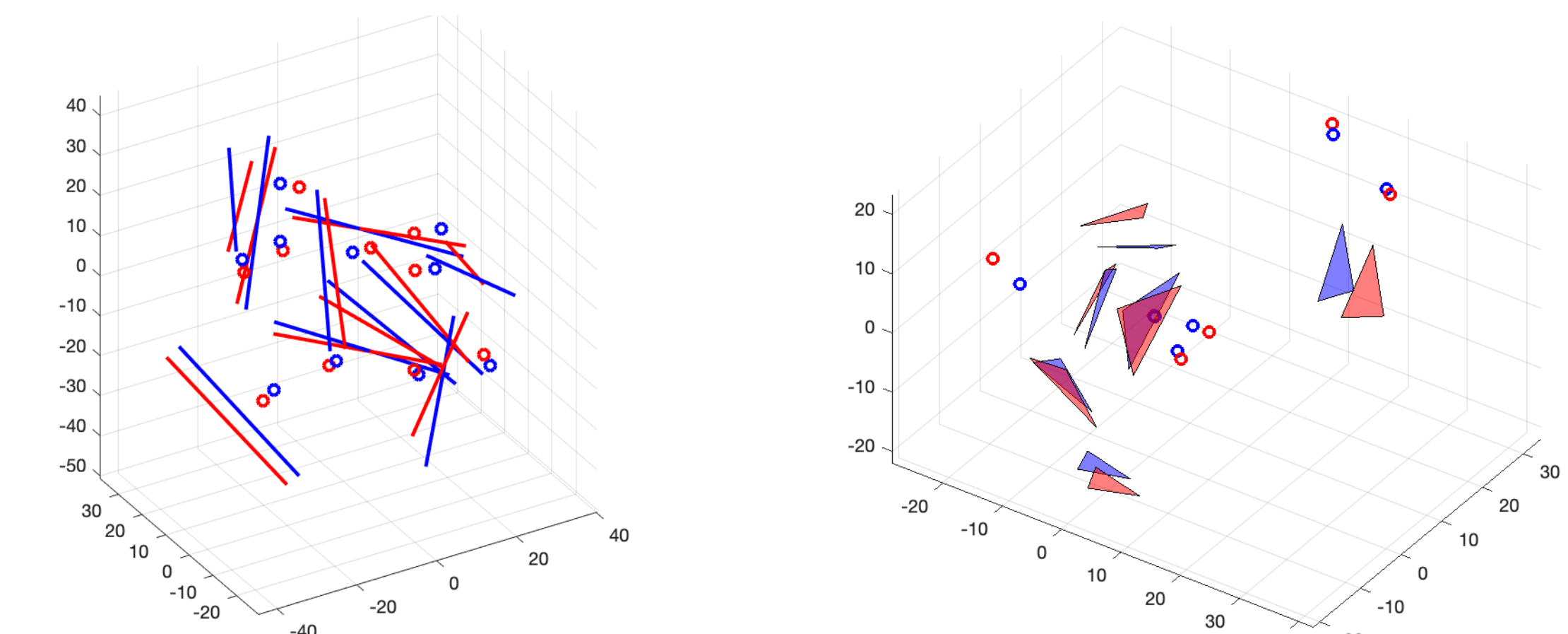
**Step 1:** Estimate the vectors  $\tilde{\mathbf{p}}_{ij}$  for a fixed  $i$  using EDM completion. The results are better when we know the distance between points  $\mathbf{x}_i$ .

**Step 2:** For a fixed  $j$ , every estimate  $\hat{\mathbf{p}}_{ij}$  of  $\tilde{\mathbf{p}}_{ij}$  should be on the same linear variety, therefore, we find the best fitting linear variety minimizing:  $E_i \left[ \|N_j(\hat{\mathbf{p}}_{ij} - \mathbf{p}_j^{\text{avg}})\|^2 \right]$ , where the rows of  $N_j$  are the orthonormal vectors normal to the linear variety and  $\mathbf{p}_j^{\text{avg}}$  is the average of the estimates over  $i$ .

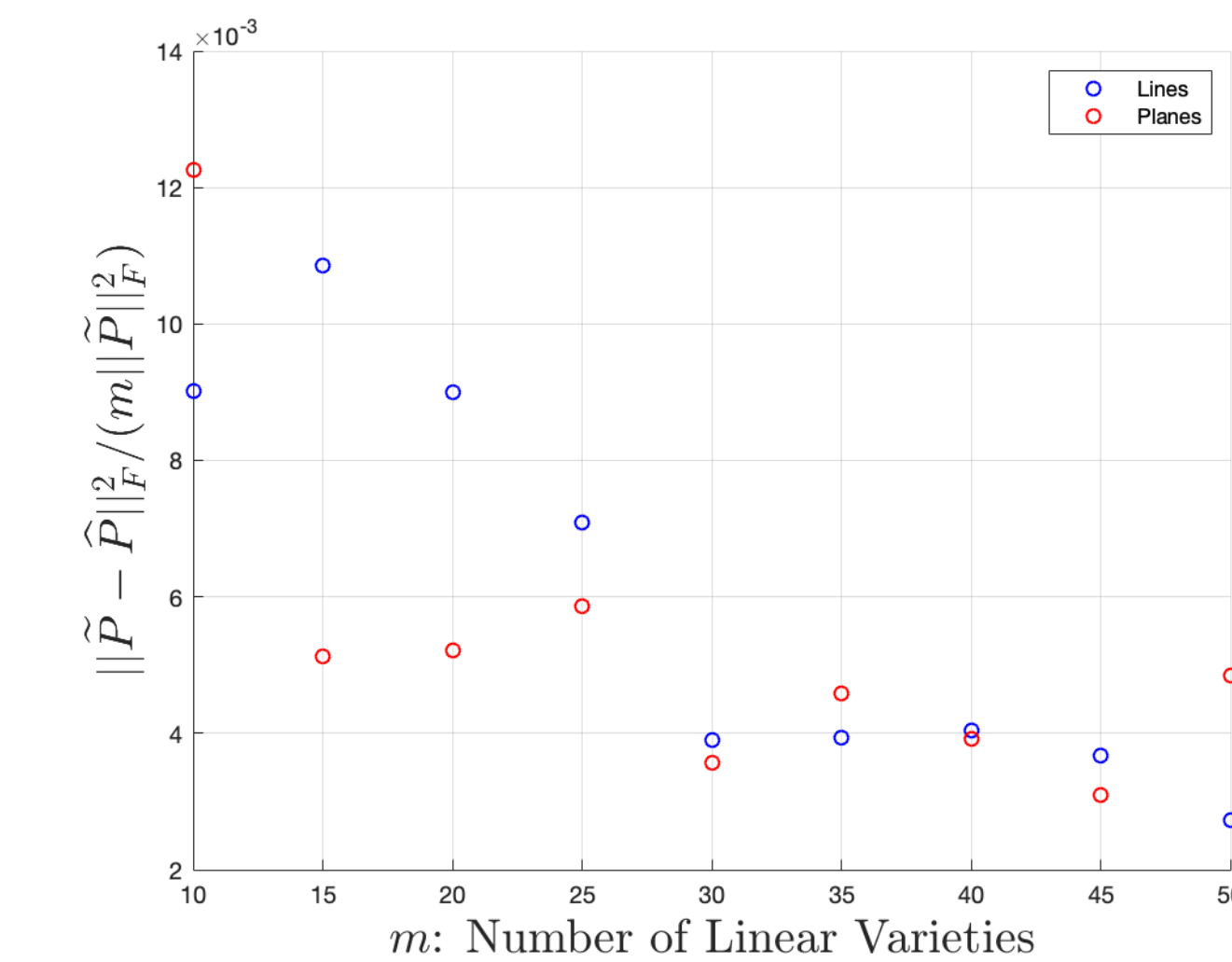


Example with 2 planes. For each cluster, we fit the plane minimizing the previous expectation.

## 5. Results



Example of reconstruction for lines and planes. Original configuration in red and estimation in blue.



Estimation error for growing number of linear varieties.

## References:

- [1] Ivan Dokmanic, Reza Parhizkar, Juri Ranieri, and Martin Vetterli. Euclidean distance matrices: essential theory, algorithms, and applications. IEEE Signal Processing Magazine, 32(6): 12–30, 2015.
- [2] Miranda Krekovic, Ivan Dokmanic, and Martin Vetterli. Omnidirectional bats, point-to-plane distances, and the price of uniqueness. In 2017 IEEE International Conference on Acoustics, Speech and Signal Processing (ICASSP), pages 3261–3265. Ieee, 2017.
- [3] Arthur M DuPré and Seymour Kass. Distance and parallelism between flats in  $\mathbb{R}^n$ . Linear Algebra and its Applications, 171:99–107, 1992.